

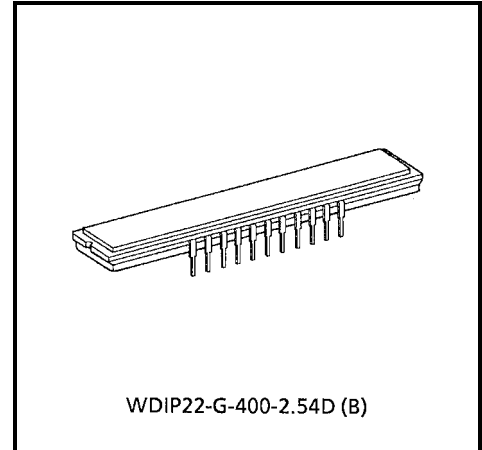
TOSHIBA CCD LINEAR IMAGE SENSOR CCD (Charge Coupled Device)

# TCD1501D

The TCD1501D which includes sample-and-hold circuit is a high sensitive and low dark current 5000 elements CCD image sensor. The sensor is designed for facsimile, imagescanner and OCR. The device contains a row of 5000 elements photodiodes which provide a 16 lines / mm (400DPI) across a A3 size paper. The device is operated by 5 V (pulse), and 12 V power supply.

## FEATURES

- Number of Image Sensing Elements : 5000 elements
- Image Sensing Element Size : 7 μm by 7 μm on 7 μm centers
- Photo Sensing Region : High sensitive and low voltage dark signal pn photodiode
- Clock : 2 Phase (5 V)
- Internal Circuit : S / H circuit
- Package : 22 pin Cerdip



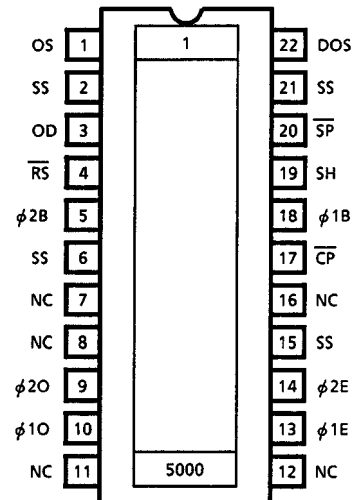
Weight : 5.2g ( Typ. )

## MAXIMUM RATINGS (Note 1)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Clock Pulse Voltage	$V_{\phi}$	-0.3~8	V
Shift Pulse Voltage	$V_{SH}$		
Reset Pulse Voltage	$V_{RS}$		
Clamp Pulse Voltage	$V_{CP}$		
Sample and Hold Pulse Voltage	$V_{SP}$		
Power Supply Voltage	$V_{OD}$		
Operating Temperature	$T_{opr}$	-25~60	°C
Storage Temperature	$T_{stg}$	-40~100	°C

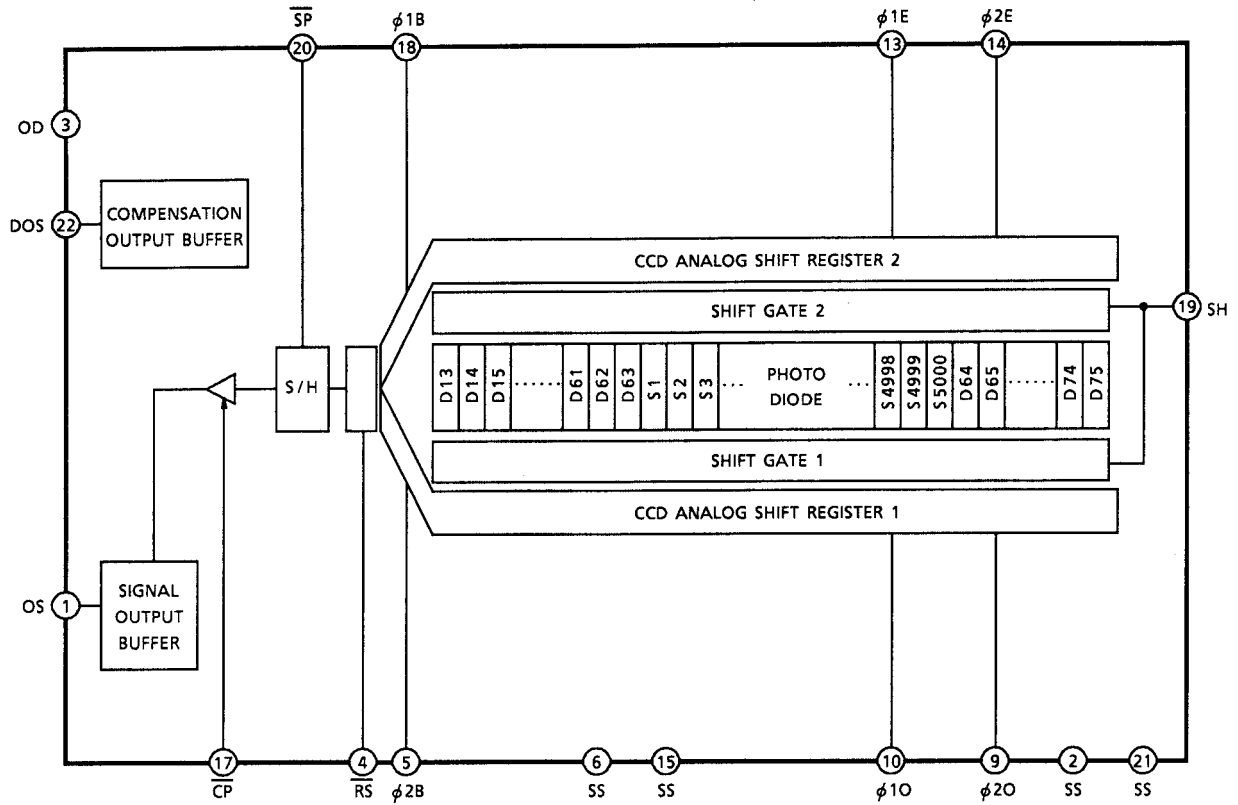
Note 1: All voltage are with respect to SS terminals (Ground).

## PIN CONNECTION



(TOP VIEW)

**CIRCUIT DIAGRAM**



**PIN NAMES**

$\phi$ 1E, O	Clock (Phase 1)
$\phi$ 2E, O	Clock (Phase 2)
$\phi$ 1B	Final Stage Clock (Phase 1)
$\phi$ 2B	Final Stage Clock (Phase 2)
SH	Shift Gate
$\overline{RS}$	Reset Gate
$\overline{SP}$	Sample and Hold Gate
$\overline{CP}$	Clamp Gate
OS	Signal Output
DOS	Compensation Output
OD	Power
SS	Ground
NC	Non Connection

**OPTICAL / ELECTRICAL CHARACTERISTICS**

(Ta = 25°C, V<sub>OD</sub> = 12 V, V<sub>φ</sub> = V<sub>RS</sub> = V<sub>SH</sub> = V<sub>SP</sub> = V<sub>CP</sub> = 5 V, f<sub>φ</sub> = 0.5 MHz, f<sub>RS</sub> = 1 MHz, t<sub>INT</sub> (INTEGRATION TIME) = 10 ms, LIGHT SOURCE = DAYLIGHT FLUORESCENT LAMP, LOAD RESISTANCE = 100 kΩ)

CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	UNIT	NOTE
Sensitivity	R	10.4	13	15.6	V / lx·s	
Photo Response Non Uniformity	PRNU	—	—	10	%	(Note 2)
	PRNU (3)	—	6	10	mV	(Note 9)
Register Imbalance	RI	—	—	3	%	(Note 3)
Saturation Output Voltage	V <sub>SAT</sub>	2	3	—	V	(Note 4)
Saturation Exposure	SE	0.13	0.23	—	lx·s	(Note 5)
Dark Signal Voltage	V <sub>DRK</sub>	—	1	2	mV	(Note 6)
Dark Signal Non Uniformity	DSNU	—	2	3	mV	(Note 6)
DC Power Dissipation	P <sub>D</sub>	—	240	325	mW	
Total Transfer Efficiency	TTE	92	—	—	%	
Output Impedance	Z <sub>o</sub>	—	0.5	1	kΩ	
Dynamic Range	DR	—	3000	—	—	(Note 7)
DC Signal Output Voltage	V <sub>OS</sub>	4	5	6.5	V	(Note 8)
DC Compensation Output Voltage	V <sub>DOS</sub>	4	5	6.5	V	(Note 8)
DC Differential Error Voltage	V <sub>OS</sub> -V <sub>DOS</sub>	—	—	400	mV	

Note 2: Measured at 50% of SE (Typ.)

$$\text{Definition of PRNU : PRNU} = \frac{\Delta\chi}{\bar{\chi}} \times 100(\%)$$

Where  $\bar{\chi}$  is average of total signal output and  $\Delta\chi$  is the maximum deviation from  $\bar{\chi}$  under uniform illumination.

Note 3: Measured at 50% of SE (Typ.)

RI is defined as follows:

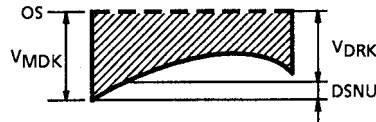
$$RI = \frac{\sum_{n=1}^{4999} |\chi_n - \chi_{n+1}|}{4999 \times \bar{\chi}} \times 100(\%)$$

Where  $\chi_n$  and  $\chi_{n+1}$  are signal output of each pixel.  $\bar{\chi}$  is average of total signal output.

Note 4: V<sub>SAT</sub> is defined as minimum saturation output voltage of all effective pixels.

Note 5: Definition of SE :  $SE = \frac{VSAT}{R} (lx \cdot s)$

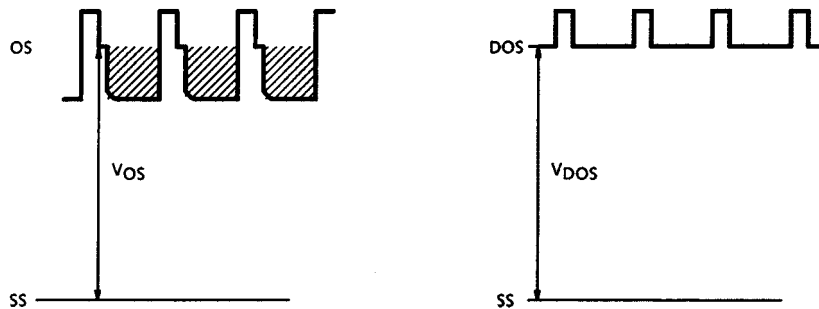
Note 6:  $V_{DRK}$  is defined as average dark signal voltage of all effective pixels.  
 $DSNU$  is defined as different voltage between  $V_{DRK}$  and  $V_{MDK}$  when  $V_{MDK}$  is maximum dark signal voltage.



Note 7: Definition of DR :  $DR = \frac{VSAT}{V_{DRK}}$

$V_{DRK}$  is proportional to  $t_{INT}$  (Integration Time).  
 So the shorter  $t_{INT}$  condition makes wider DR values.

Note 8: DC signal output voltage and DC compensation output voltage are defined as follows:



Note 9: PRUN (3) is defined as maximum voltage with next pixel, where measured 5% of SE (Typ.).

## OPERATING CONDITION

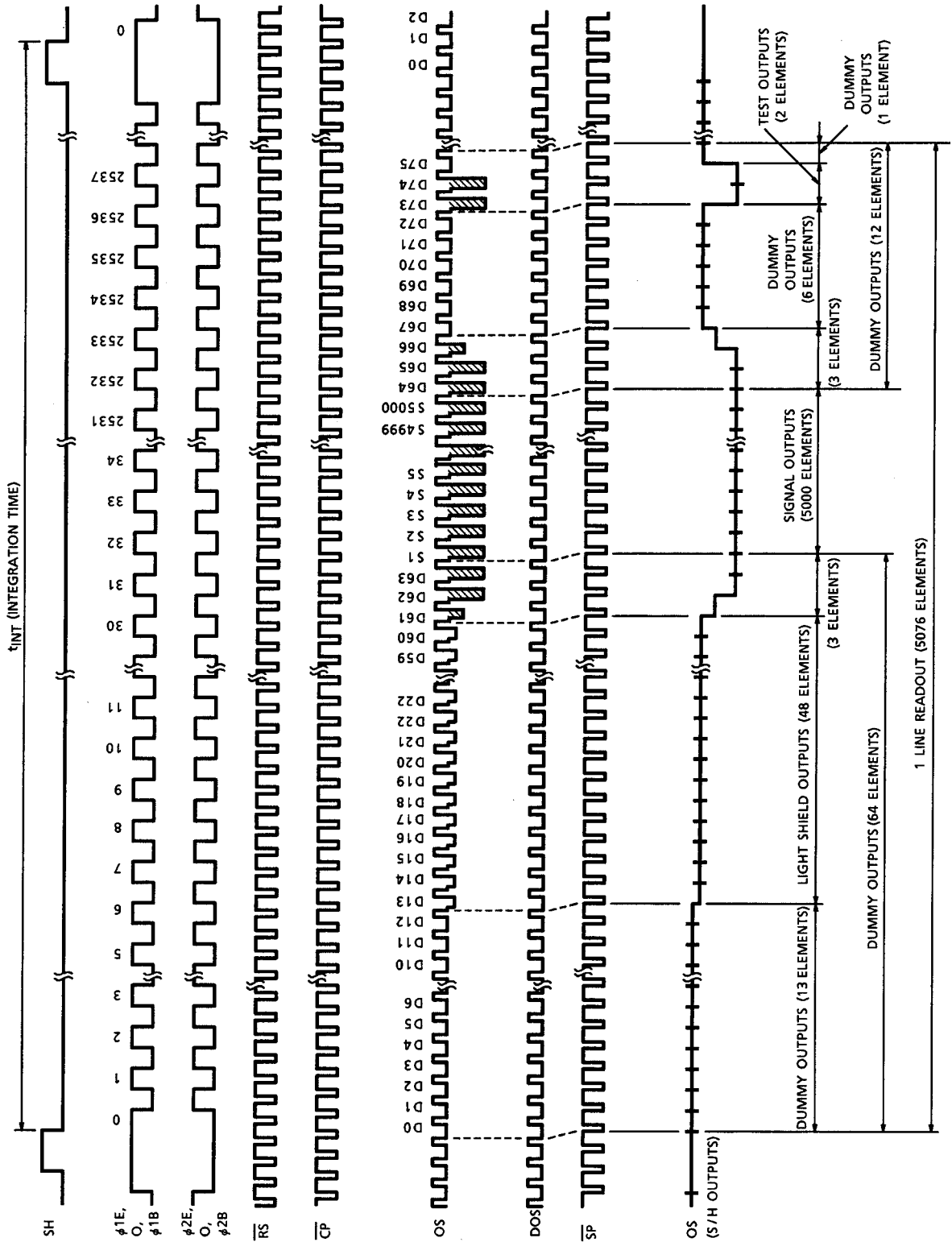
CHARACTERISTIC		SYMBOL	MIN.	TYP.	MAX.	UNIT
Clock Pulse Voltage	"H" Level	$V_{\phi 1E, O}$ $V_{\phi 2E, O}$	4.5	5	5.5	V
	"L" Level		0	—	0.5	
Final Stage Clock Voltage	"H" Level	$V_{\phi 1B}$ $V_{\phi 2B}$	4.5	5	5.5	V
	"L" Level		0	—	0.5	
Shift Pulse Voltage	"H" Level	$V_{SH}$	4.5	5	5.5	V
	"L" Level		0	—	0.5	
Reset Pulse Voltage	"H" Level	$V_{RS}$	4.5	5	5.5	V
	"L" Level		0	—	0.5	
Clamp Pulse Voltage	"H" Level	$V_{CP}$	4.5	5	5.5	V
	"L" Level		0	—	0.5	
Sample and Hold Pulse Voltage *	"H" Level	$V_{SP}$	4.5	5	5.5	V
	"L" Level		0	—	0.5	
Power Supply Voltage		$V_{OD}$	11.4	12.0	13.0	V

\*: Supply "L" level to  $\overline{SP}$  terminal when sample-and-hold circuitry is not used.

## CLOCK CHARACTERISTICS (Ta=25°C)

CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	UNIT
Clock Pulse Frequency	$f_{\phi}$	—	0.5	6.0	MHz
Reset Pulse Frequency	$f_{\overline{RS}}$	—	1.0	12.0	MHz
Sample and Hold Pulse Frequency	$f_{\overline{SP}}$	—	1.0	12.0	MHz
Clock Capacitance	$C_{\phi E}$	—	350	450	pF
	$C_{\phi O}$	—	350	450	
Final Stage Clock Capacitance	$C_{\phi B}$	—	10	20	pF
Shift Gate Capacitance	$C_{SH}$	—	10	20	pF
Reset Gate Capacitance	$C_{\overline{RS}}$	—	10	20	pF
Clamp Gate Capacitance	$C_{\overline{CP}}$	—	10	20	pF
Sample and Hold Gate Capacitance	$C_{\overline{SP}}$	—	10	20	pF

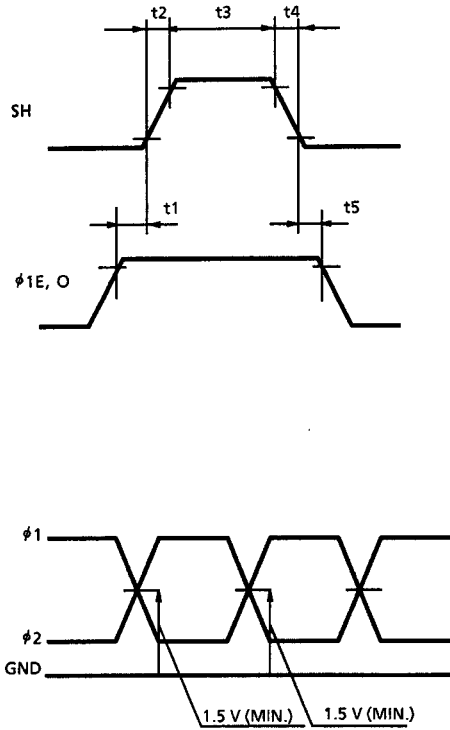
TIMING CHART



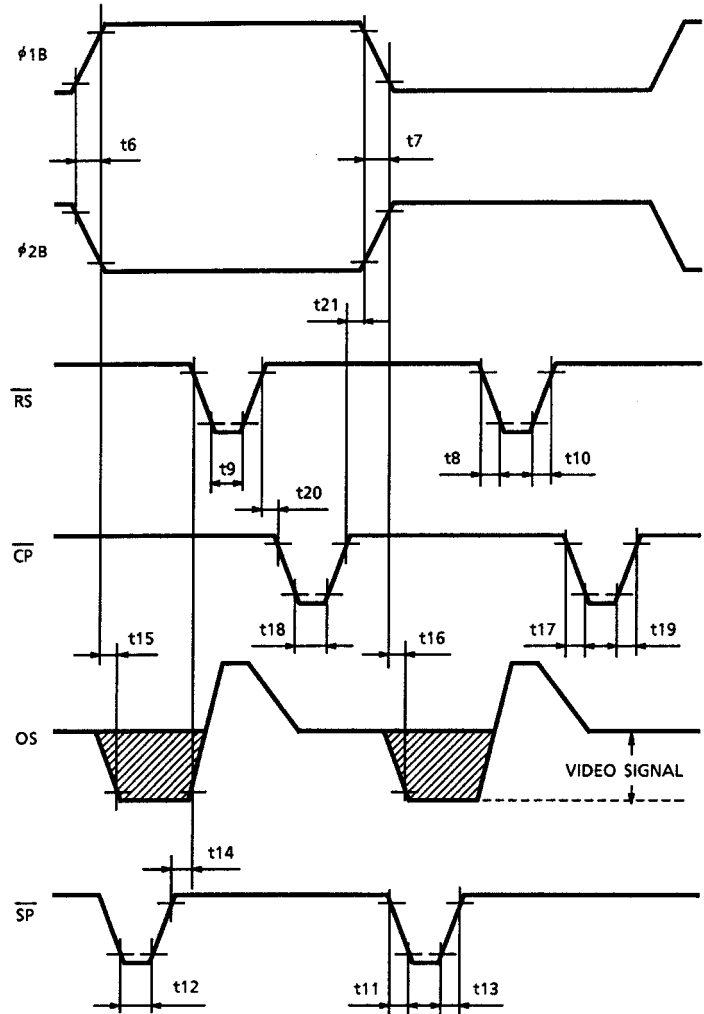
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## TIMING REQUIREMENTS

SH,  $\phi 1$  TIMING



$\phi 1, \phi 2, \overline{RS}, \overline{CP}, OS, \overline{SP}$  TIMING



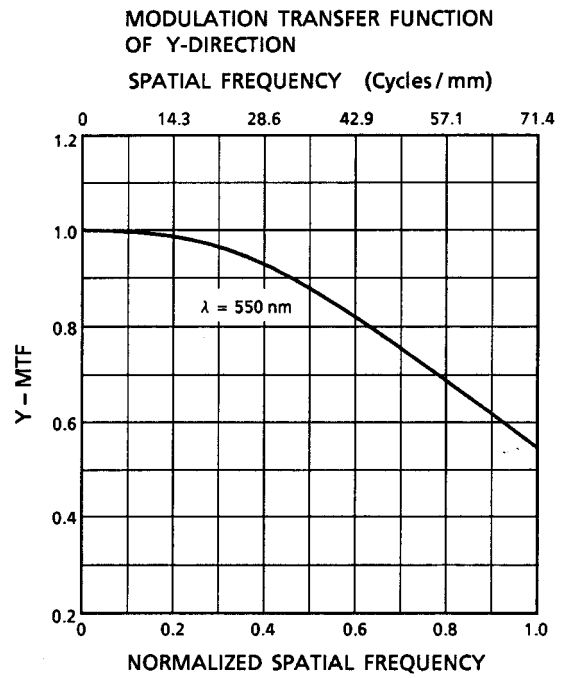
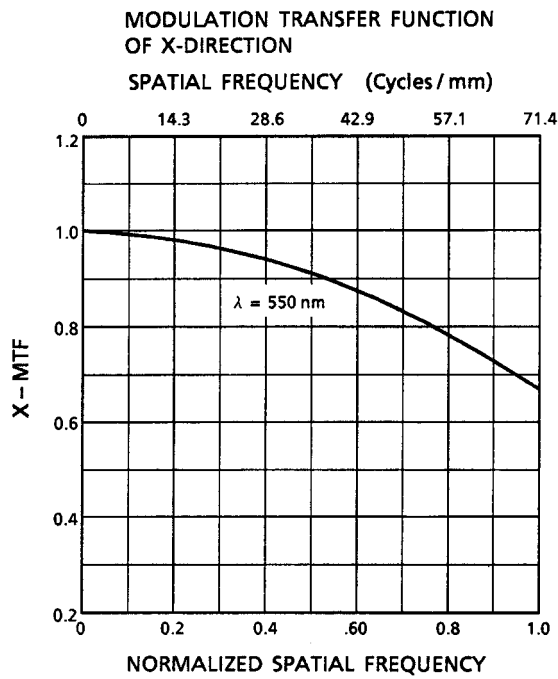
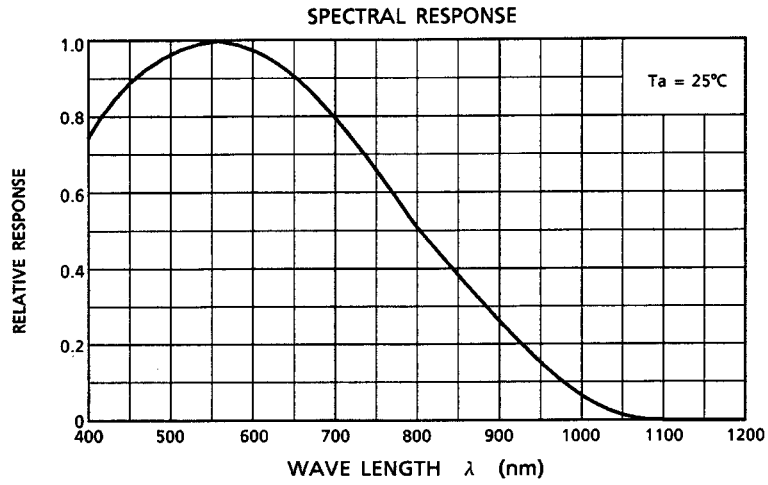
CHARACTERISTIC	SYMBOL	MIN.	TYP. (Note 10)	MAX.	UNIT
Pulse Timing of SH and $\phi_{10}$ , E	t1, t5	100	300	—	ns
SH Pulse Rise Time, Fall Time	t2, t4	0	50	—	ns
SH Pulse Width	t3	500	1000	—	ns
$\phi_1$ , $\phi_2$ Pulse Rise Time, Fall Time	t6, t7	0	100	—	ns
$\overline{RS}$ Pulse Rise Time, Fall Time	t8, t10	0	20	—	ns
$\overline{RS}$ Pulse Width	t9	20	250	—	ns
$\overline{SP}$ Pulse Rise Time, Fall Time	t11, t13	0	20	—	ns
$\overline{SP}$ Pulse Width	t12	20	—	—	ns
Pulse Timing of $\overline{SP}$ and $\overline{RS}$	t14	0	50	—	ns
Video Data Delay Time (Note 11)	t15, t16	—	30	—	ns
$\overline{CP}$ Pulse Rise Time, Fall Time	t17, t19	0	20	—	ns
$\overline{CP}$ Pulse Width	t18	20	—	—	ns
Pulse Timing of $\overline{RS}$ and $\overline{CP}$	t20	0	—	—	ns
Pulse Timing of $\phi_{1B}$ , $\phi_{2B}$ and $\overline{CP}$	t21	0	—	—	ns

Note 10: TYP. is the case of  $f_{RS} = 1.0$  MHz

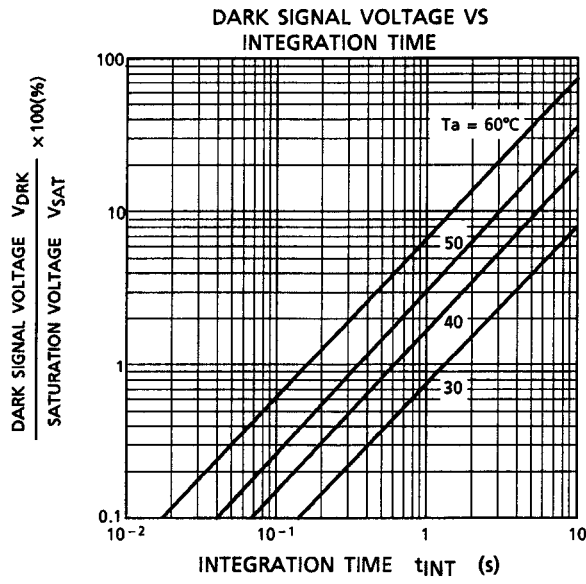
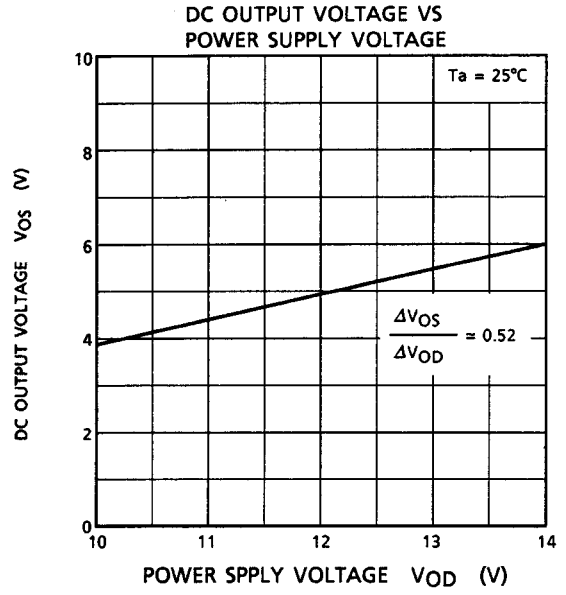
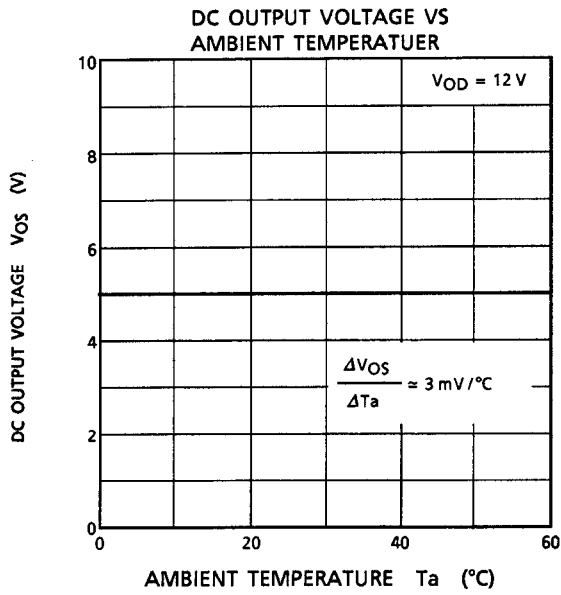
Note 11: Load Resistance is 100 k $\Omega$



**TYPICAL PERFORMANCE CURVES**



**TYPICAL PERFORMANCE CURVES(Cont.)**



**CAUTION****1. Window Glass**

The dust and stain on the glass window of the package degrade optical performance of CCD sensor.

Keep the glass window clean by saturating a cotton swab in alcohol and lightly wiping the surface, and allow the glass to dry, by blowing with filtered dry N<sub>2</sub>. Care should be taken to avoid mechanical or thermal shock because the glass window is easily to damage.

**2. Electrostatic Breakdown**

Store in shorting clip or in conductive foam to avoid electrostatic breakdown.

CCD Image Sensor is protected against static electricity, but interior puncture mode device due to static electricity is sometimes detected. In handing the device, it is necessary to execute the following static electricity preventive measures, in order to prevent the trouble rate increase of the manufacturing system due to static electricity.

- a. Prevent the generation of static electricity due to friction by making the work with bare hands or by putting on cotton gloves and non-charging working clothes.
- b. Discharge the static electricity by providing earth plate or earth wire on the floor, door or stand of the work room.
- c. Ground the tools such as soldering iron, radio cutting pliers or pincer.

It is not necessarily required to execute all precaution items for static electricity.

It is all right to mitigate the precautions by confirming that the trouble rate within the prescribed range.

**3. Incident Light**

CCD sensor is sensitive to infrared light. Note that infrared light component degrades resolution and PRNU of CCD sensor.

**4. Lead Frame Forming**

Since this package is not strong against mechanical stress, you should not reform the lead frame.

We recommend to use a IC-inserter when you assemble to PCB.

**5. Soldering**

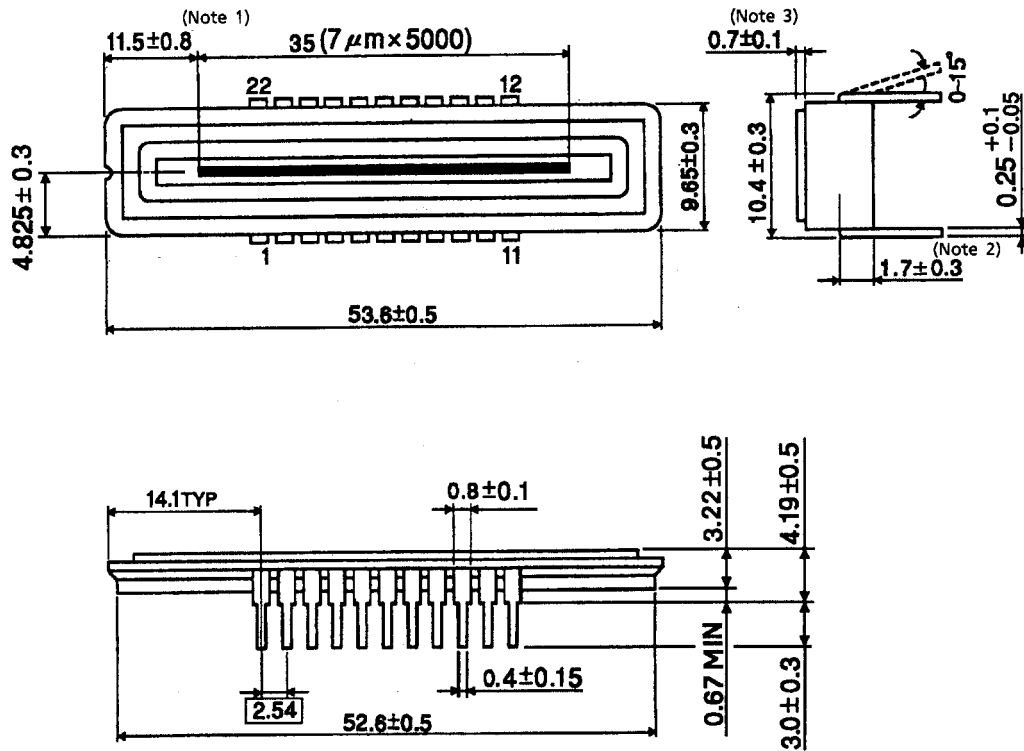
Soldering by the solder flow method cannot be guaranteed because this method may have deleterious effects on prevention of window glass soiling and heat resistance.

Using a soldering iron, complete soldering within ten seconds for lead temperatures of up to 260°C, or within three seconds for lead temperatures of up to 350°C.

**PACKAGE DIMENSIONS**

WDIP22-G-400-2.54D (B)

Unit : mm



Note 1: No. 1 SENSOR ELEMENT (S1) TO EDGE OF PACKAGE.

Note 2: TOP OF CHIP TO BOTTOM OF PACKAGE.

Note 3: GLASS THICKNES (n = 1.5)

Weight : 5.2 g (Typ.)

**RESTRICTIONS ON PRODUCT USE**

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